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P. Walker
7-1-03IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Peter G. Borden and Ji-Ping Li
 Assignee: Applied Materials, Inc.
 Title: Identifying Defects In A Conductive Structure Of A Wafer, Based On Heat Transfer Therethrough
 Serial No.: 10/090,287 Filing Date: March 1, 2002
 Examiner: Verbitsky, Gail Group Art Unit: 2859
 Docket No.: BOX014 US Confirmation No.: 6609

Santa Clara, California
 June 25, 2003

COMMISSIONER FOR PATENTS
 P.O. Box 1450
 Alexandria, VA 22313-1450

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JUN 25 2003

AMENDMENT

TECHNOLOGY CENTER 2800

Dear Sir:

A. Introductory Comments

This Amendment is responsive to the Office Action dated March 26, 2003, which has a statutorily shortened period for response that ends June 26. Please enter the following amendments before taking action on the merits of the above-referenced application.

The following amendments are presented in a format set forth in a "Revised Notice AMENDMENTS MAY NOW BE SUBMITTED IN REVISED FORMAT" which is essentially same as the format being considered for adoption in July 2003 by revision 1.37 C.F.R. 1.121 (Manner of Making Amendments). Specifically, in the following amendments, the text being added is shown underlined and the text being deleted is shown struck through. Moreover, only a marked up version of each replacement paragraph and each replacement claim is provided below (because a clean copy is no longer required).

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 02 FC:120